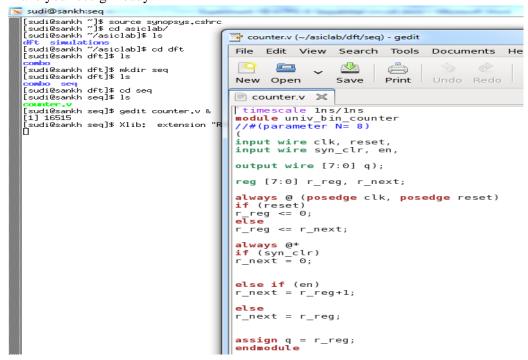
# ASIC Design Lab (EC-6272)

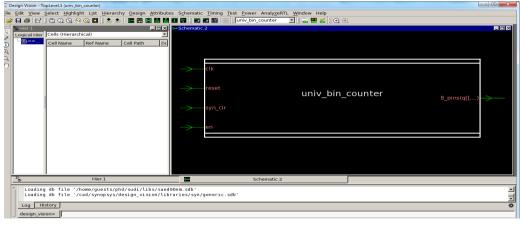
## Experiment – VII (ATPG-II)

## ATPG for Sequential circuits

- 1. Open the terminal
- 2. Source the synopsys.cshrc
- 3. In a ASIC lab directory, make design.v (any sequential circuit). In this experiment, we perform ATPG (Automatic Test Pattern Generation) for Sequential circuit. In our previous experiment we have performed ATPG for combinational circuits. Scan insertion is not required for combinational circuits, but it is required for sequential circuits. Scan insertion can be done in DFT compiler which is a integral part of design vision.
- 4. Open the design vision and execute the following commands. We generate scan inserted synthesized netlist at the end. We also extract spf (STIL procedure file), which is a input to the Tetramax used for ATPG. (Note: STIL: Standard Test Interface Language).
- 5. Make your design ready.



6. Open design\_vision. Read the library and design into design vision.



7. Go the terminal as below and execute the following commands to insert dft (scan chain) and spf file.

8. Execute the following commands:-

```
kheck_design

set_scan_configuration -style multiplexed_flip_flop

link

create_port -direction in [list test_si]
create_port -direction out [list test_so]
create_port -direction in test_en

set_dft_signal -view existing_dft -type reset -port reset -active_state 1
set_dft_signal -view existing_dft -type ScanClock -timing {45 55} -port clk
set_dft_signal -view spec -type scanDataIn -port [list test_si]
set_dft_signal -view spec -type scanDataOut -port [list test_so]
set_dft_signal -view spec -type scanEnable -port test_en -active_state 1

create_test_protocol
dft_drc -verbose

set_scan_configuration -chain_count 1
compile -scan
preview_dft
insert_dft
write_test_protocol -output counter.spf
```

```
in routine univ_bin_counter line 12 in file
    '/home/guests/phd/sudi/asiclab/dft/seq/counter.v'.
                            I Type
                                           | Width | Bus | MB | AR | AS | SR | SS | ST |
      Register Name
                                                    I Y IN IY IN IN IN IN I
                            | Flip-flop |
                                               8
        r_reg_reg
                     _____<u>.</u>
Presto compilation completed successfully.
Current design is now '/home/guests/phd/sudi/asiclab/dft/seq/univ_bin_counter.db:univ_bin_counter'
Loaded 1 design.
Loaded 1 design.
Current design is 'univ_bin_counter'.
design_vision> Current design is 'univ_bin_counter'.
Loading db file '/home/guests/phd/sudi/libs/saed90nm.sdb'
Loading db file '/cad/synopsys/design_vision/libraries/syn/generic.sdb'
design_vision> check_design
************
Total
                                                                                      1
     Cells do not drive (LINT-1)
Warning: In design 'univ_bin_counter', cell 'C73' does not drive any nets. (LINT-1)
_
design_vision> ▮
```

9. Execute all DFT related commands as below: -

```
🔀 sudi@sankh:seq
  Loading db file '/cad/synopsys/design_vision/libraries/syn/generic.sdb'
  design_vision> check_design
  *************
 check_design summary:
Version: K-2015.06-SP2-1
               Fri Mar 16 15:08:43 2018
  Date:
  ************
                     Name
                                                                      Total
  Cells
     Cells do not drive (LINT-1)
  Warning: In design 'univ_bin_counter', cell 'C73' does not drive any nets. (LINT-1)
  Accepted scan configuration for modes: all_dft
  design_vision> link
   Linking design 'univ_bin_counter'
   Using the following designs and libraries:
   saed90nm_typ (library)
                               /home/guests/phd/sudi/libs/saed90nm_typ.db
 design_vision> create_port -direction in [list test_si]
Creating port 'test_si' in design 'univ_bin_counter'.
 design_vision> create_port -direction out [list test_so]
Creating port 'test_so' in design 'univ_bin_counter'.
 design_vision> create_port -direction in test_en
Creating port 'test_en' in design 'univ_bin_counter'.
 design_vision> set_dft_signal -view existing_dft -type reset -port reset -active_state 1
 Accepted dft signal specification for modes: all_dft
  design_vision> set_dft_signal -view existing_dft -type ScanClock -timing {45 55} -port clk
 Accepted dft signal specification for modes: all_dft
 design_vision> set_dft_signal -view spec -type scanDataOut -port [list test_so]
 Accepted dft signal specification for modes: all_dft
 design_vision> set_dft_signal -view spec -type scanEnable -port test_en -active_state 1
Accepted dft signal specification for modes: all_dft
 design vision>
```

#### 10. Continue

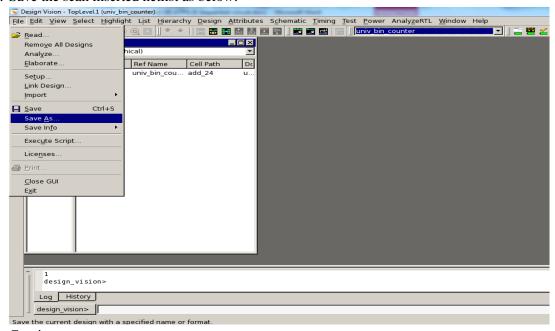
```
Hccepted d+t signal specification for modes: all_d+t
design_vision> create_test_protocol
In mode: all_dft...
Information: Starting test protocol creation. (TEST-219)
...reading user specified clock signals...
Information: Identified system/test clock port clk (45.0,55.0). (TEST-265)
...reading user specified asynchronous signals...
Information: Identified active high asynchronous control port reset. (TEST-266)
design_vision> dft_drc -verbose
 In mode: all_dft..
  Pre-DFT DRC enabled
 Information: Starting test design rule checking, (TEST-222)
  Loading test protocol
  ...checking vector rules...
  ...checking pre-dft rules...
  DRC Report
  Total violations: 0
Test Design rule checking did not find violations
Information: Test design rule checking completed. (TEST-123)
Current design is 'univ_bin_counter'.
Current design is 'univ_bin_counter'.
Warning: The current design contains unmapped components. The output netlist might not be read back into the system. (TEST-268)
design_vision> set_scan_configuration -chain_count 1
Accepted scan configuration for modes: all_dft
design_vision> ▮
```

#### 11. Continue: -

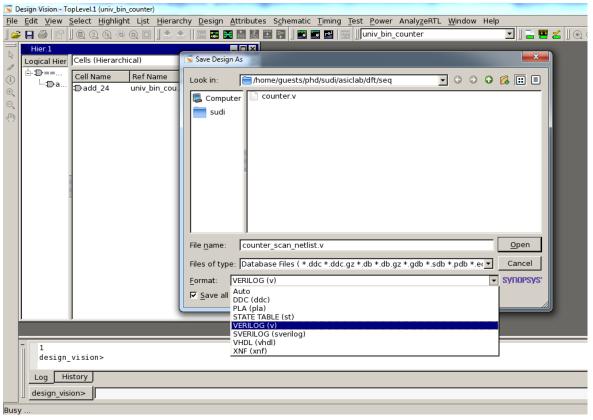
### 12. Continue: -

```
🔀 sudi@sankh:seq
   design_vision> preview_dft
  Information: Starting test design rule checking. (TEST-222)
Test Design rule checking did not find violations
Information: Test design rule checking completed. (TEST-123)
     Architecting Scan Chains
  Number of chains: 1
Scan methodology: full_scan
   Scan style: multiplexed_flip_flop
  Clock domain: no_mix
Scan enable: test_en (no hookup pin)
  Scan chain '1' (test_si --> test_so) contains 8 cells
   ******** Test Point Plan Report *******
  **********************
  design_vision> insert_dft
Loading db file '/home/guests/phd/sudi/libs/saed90nm_typ.db'
  Information: Starting test design rule checking, (TEST-222)
Test Design rule checking did not find violations
Information: Test design rule checking completed, (TEST-123)
     Architecting Scan Chains
    Routing Scan Chains
Routing Global Signals
Mapping New Logic
  Resetting current test mode
  design_vision> write_test_protocol -output counter.spf
Writing test protocol file '/home/guests/phd/sudi/asiclab/dft/seq/counter.spf' for mode 'Internal_scan'...
  design_vision> ▮
```

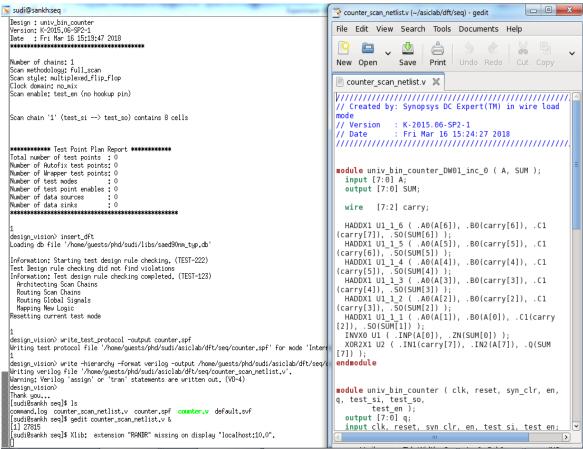
13. Save the scan inserted netlist as below: -



14. Continue: -



- 15. File- Exit- Design \_Vision.
- 16. Open the counter\_scan\_netlist.v and observe the difference between your earlier counter\_net.v and scan inserted counter\_scan\_netlist.v



### 17. Open the Tetramax and generate ATPG

### 18. Simulate the ATPG using VCS as before.